Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10633617	SHIN ET AL.
Examiner	Art Unit
Nhon T Diep	2621

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES			
Search Notes	Date	Examiner	
East search	6/8/2008	ND	

INTERFERENCE SEARCH				
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